

**Search Notes**

Application/Control No.

10/066,188

Examiner

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Applicant(s)/Patent under  
Reexamination

TEIG ET AL.

Art Unit

2825

**SEARCHED**

Class	Subclass	Date	Examiner
716	12	8/15/2005	JSL
716	14	8/15/2005	JSL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST [USPAT;US- PGPUB;EPO;JPO;DERWENT;IBM_T DB]	8/15/2005	JSL
EAST [USPAT;US- PGPUB;EPO;JPO;DERWENT;IBM_T DB]	9/1/2005	JSL
IEEE	8/15/2005	JSL